

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/509,167 REHSE, HEINO	
		Examiner	Art Unit EDWARD PARK	2624 Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0117675 a1	06-2003	Shirato et al.	358/505
	B	US-			
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	D	US-			
	E	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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	N	WO/2002/019270	03-2002	JAPAN	Shirato et al	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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